

FEATURES

- ☐ CMOS EE Technology
- ☐ Single 5 V supply
- ☐ Reliable CMOS floating gate process
- ☐ 18-pin DIP package
- ☐ Self-timed write operation
- Multiplexed address and data bus
- □ Data polling
- ☐ 10,000 erase/write cycles
- ☐ Minimum 10 years data retention



SC22201CN

18-PIN DIP



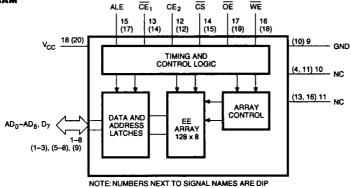
GENERAL DESCRIPTION

The SC22101 and SC22201 are 128 by 8 programmable, non-volatile, parallel access memories built with Sierra's proprietary CMOS floating gate process. Data and address lines are multiplexed, enabling these devices to be packaged in an 18-pin DIP, saving board space. The pin-out is identical to the Intel 8185 static RAM and the 2001 Nonvolatile RAM, allowing the memories to directly interface with Intel and other popular 8-bit and 16-bit microprocessors and microcontrollers.

The write cycle is simplified by a self-timed erase before write circuit on-chip. The end of write cycle can be determined by polling the data pins, or the controller can simply allow a minimum time between a write command and the subsequent command. To prevent undesirable modification of the memory contents during system power up or power down, a lockout circuit ignores write commands while V_{CC} is below the prescribed level of VLKO.

Applications for these memories include storing position data in robotic systems, storing local area network node address and parameter settings in data communications equipment, storing set-up and last position data in industrial control systems and storing PBX switch data in telecommunications equipment.

BLOCK DIAGRAM



PIN NUMBERS; NUMBERS IN () ARE SOIC PIN

NUMBERS.

PIN DESCRIPTIONS

| PIN* | NAME | DESCRIPTION |
|--------------------------|---|--|
| 1–8 (1–3), (5–8), (9) | AD ₀ -AD ₆ , D ₇ | Multiplexed address and data bits. D ₇ , Pin 8 and Pin (9), is DATA only. |
| (4) | NC | No connection |
| 9 (10) | GND | Ground, 0 V. |
| 10 (11) | NC | No connection |
| 11 (13) | NC | No connection. No internal connection is made to this pin and it may be left floating. |
| 12 (12) | CE2 | Chip Enable 2 (see Table 1) |
| 13 (14) | CE1 | Chip Enable 1 (see Table 1) |
| 14 (15) | CS | Chip Select (see Table 1) |
| (16) | NC | No connection |
| 15 (17) | ALE | Address Latch Enable |
| 16 (18) | WE | Write Enable |
| 17 (19) | ŌĒ | Output Enable |
| 18 (20) | v _{cc} | Positive power supply, 5 V. |

^{*} Pin numbers not in () are for 18-pin DIP; those in () are for 20 pin SOIC.

FUNCTIONAL DESCRIPTION

Table 1 shows the different modes of operation as a function of the control signals. Standby powered down mode: Both write and read are inhibited and the device's power consumption is greatly reduced. Standby powered up mode: the device consumes the operating power, but read and write are inhibited. Inhibit mode: the device is write protected to avoid inadvertent modifications while the read and write pins are changing.

Read Operation

Figure 2 shows the timing diagram for READ operation. The address as well as the states of $\overline{\text{CE1}}$ and CE2 are latched on the falling edge of ALE. Pins 1 through 7 are used for address bits.

Data appear on pins 1 through 8 after OE becomes active (low).

Write Operation

Write operation's timing is shown in Figure 3. Similar to the READ operation, the address and states of CE1 and CE2 are latched on the falling edge of the ALE. After the address is latched, the WE becomes active (low) for the minimum time of TCC and returns to inactive state. This initiates the internally timed write operation. No external erase before write operation is needed and data lines as well as control lines may change after the write operation is initiated.

DATA Polling

After the write operation is initiated, its conclusion can be monitored by putting the device in the READ mode and polling the D7 data bit. The data bit will be logical inverse of the bit being written to a location in memory until the write operation is completed. At this time the D7 data bit will be the same as the last D7 data bit written into memory.

Write Lockout

During system power up or power down, an on-chip write lockout circuit prevents spurious WRITES into the memory locations while $V_{\rm CC}$ is lower than the specified lockout voltage VLKO. This frees the system designer from having to design external write protection circuits.

| MODE | CE1 | CE2 | CS | ŌĒ | WE | AD ₀ -AD ₇ |
|----------------------|-----------------|-----------------|-----------------|-----------------|-----------------|----------------------------------|
| Standby Powered Down | V _{IH} | X | Х | х | Х | Hi-Z |
| Standby Powered Down | X | V _{IL} | Х | Х | Х | Hi-Z |
| Standby Powered Up | V _{IL} | V _{IH} | V _{IH} | х | х | Hi-Z |
| Read | V _{IL} | V _{IH} | V _{IL} | V _{IL} | V _{IH} | Data Out |
| Write | V _{IL} | V _{IH} | V _{IL} | V _{IH} | V _{IL} | Data In |
| Inhibit | V _{IL} | V _{IH} | V _{IL} | V _{IH} | V _{IH} | Hi-Z |
| Inhibit | V _{IL} | V _{IH} | V _{IL} | V _{IL} | V _{IL} | Hi-Z |

Notes:

 $egin{array}{ll} V_{
m lL} &= {
m Logical\,Low\,Input} & V_{
m lH} &= {
m Logical\,High\,Input} \\ {
m Hi-Z} &= {
m High\,Impedance\,State} & X &= {
m Don't\,Care} \end{array}$

A C TEST CONDITIONS

The CE1 and CE2 inputs are latched by the falling edge of ALE.

Table 1. Modes

| ABSOLUTE MAXIMUM RATINGS (Note 1) | | | | | |
|---|-------------------------------------|--|--|--|--|
| Supply Voltage, V _{CC} | 7 V | | | | |
| Voltage on Any Pin | V _{CC} +0.5 V GND-0.5 V | | | | |
| Storage Temperature Range | −65 to +150°C | | | | |
| Maximum Power Dissipation @ 25°C (Note 2) | 500 mW | | | | |
| Lead Temperature (Soldering 10 s) | 300°C | | | | |

| Output Load 1TTL gate and $C_L = 100 \text{ pF}$ | | | | | | | |
|--|--|--|--|--|--|--|--|
| 20 ns | | | | | | | |
| 0.0 V to 3.0 V | | | | | | | |
| 0.8 V and 2.0 V | | | | | | | |
| | | | | | | | |

OPERATING CONDITIONS (Applies to DC and AC Characteristics)

| | PARAMETER | DESCRIPTION | CONDITIONS | MIN | TYP | MAX | UNITS |
|---|-----------------|-------------------------|------------|-----|-----|-----|-------|
| ı | T _A | Ambient Temperature | | 0 | | 70 | •℃ |
| | v _{cc} | Positive Supply Voltage | | 4.5 | 5.0 | 5.5 | V |

DC ELECTRICAL CHARACTERISTICS

| | | | SC22101 | | SC22201 | | | | |
|------------------|---|--------------------------|---------|-----|----------------------|------|--------|----------------------|-------|
| PARAM. | DESCRIPTION | CONDITIONS | MIN | TYP | MAX | MIN | TYP | MAX | UNITS |
| V _{OH} | Output High Voltage | $I_{OH} = -400 \mu A$ | 2.4 | | | 2.4 | | | v |
| V _{OL} | Output Low Voltage | I _{OL} = 2.1 mA | | | 0.4 | | | 0.4 | V |
| V _{IH} | High Level Input Voltage | | 2.0 | | V _{cc} +0.5 | 2.0 | | V _{cc} +0.5 | V |
| V _{IL} | Low Level Input Voltage | | -0.5 | | 0.8 | -0.5 | | 0.8 | V |
| V _{LKO} | V _{CC} Level for Write Lockout | | 4.0 | | 4.4 | 3.8 | | 4.4 | V |
| I _{LI} | Input Leakage Current | $V_{IN} = V_{CC}$ | | | ±10.0 | | | ±10.0 | μA |
| I _{LO} | Output Leakage Current | $V_{OUT} = V_{CC}$ | | | ±10.0 | | | ±10.0 | μА |
| I _{cc} | Operating Supply Current | TTL Inputs | | | 15.0 | | | 15.0 | mA |
| -60 | operating supply success | CMOS Inputs | | | 10.0 | | | 10.0 | mA |
| ICCPD | Standby Supply Current | TTL Inputs | | | 5.0 | | | 5.0 | mA |
| CCPD | | CMOS Inputs | | | 100 | | | 100 | μА |
| I _{sc} | Short-Circuit Current | 1 Output Pin Shorted | | 40 | | | 40 | | mA |
| | Endurance | | 10,000 | | | | 10,000 | | |

- Notes: 1. "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range", the device should not be operated at these limits. The table of "Electrical Characteristics" provides actual operating limits.
 - 2. Power dissipation temperature derating---Plastic "N" package: -12 mW/°C from 65°C to 85°C.

CAPACITANCE (T_A = 25°C, f = 1 MHz) (Note 3)

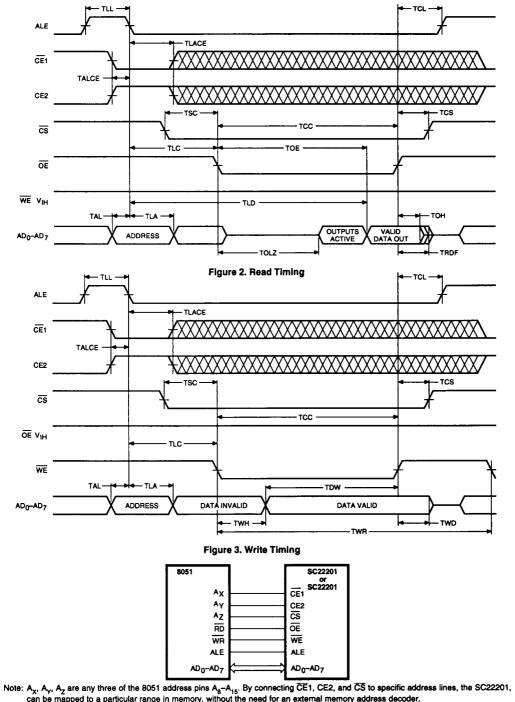
| l | PARAMETER | DESCRIPTION | CONDITIONS | MIN | TYP | MAX | UNITS |
|---|------------------|--------------------------|--|-----|-----|-----|-------|
| | C _{IN} | Input Capacitance | V _{IN} = 0 V | | 5 | 10 | pF |
| | C _{1/0} | Input/Output Capacitance | $\overline{OE} = \overline{CE1} = \overline{CS} = V_{IH}$ $CE2 = V_{IL}$ | | | 10 | pF |

Note: 3. These parameters are sampled and not 100% tested.

AC CHARACTERISTICS

| | | SC | 22101 | sca | 22201 | |
|------------|---|-----|-------|-----|-------|-------|
| PARAMETER* | DESCRIPTION | MIN | MAX | MIN | MAX | UNITS |
| TAL | Address to Latch Setup Time | 50 | | 50 | ļ | ns |
| TLA | Address Hold Time After Latch | 45 | | 45 | | ns |
| TLC | Latch to OE/WE Control | 80 | | 80 | | ns |
| TOE | Valid Data Out Delay from Read Control | | 170 | | 170 | ns |
| TLD | ALE to Data Out Valid | | 300 | | 300 | ns |
| TLL | Latch Enable Width | 100 | | 100 | | ns |
| ТОН | Output Held from Addresses, CS, or OE (whichever changes first) | 0 | | 0 | | ns |
| TOLZ | OE Low to Output Driven | 10 | | 10 | | ns |
| TRDF | Data Bus Float After Read | 0 | | 0 | 95 | ns |
| TCL | OE/WE Control to Latch Enable | 0 | | 0 | | ns |
| TCC | OE/WE Control Width | 250 | | 250 | | ns |
| TDW | Data In to Write Setup Time | 150 | | 150 | | ns |
| TWD | Data In Hold Time After Write | 20 | | 20 | | ns |
| TSC | Chip Select Set-Up to OE/WE Control | 0 | | 50 | | ns |
| TCS | Chip Select Hold Time After OE/WE Control | 0 | | 10 | | ns |
| TALCE | Chip Enable Set-Up to ALE Falling | 30 | | 30 | | ns |
| TLACE | Chip Enable Hold Time After ALE Falling | 45 | | 45 | | ns |
| TWR | Byte Write Cycle Time | | 20 | | 40 | ms |
| TWH | Data Invalid After WE Falling | | 1 | | 1 | ms |

^{*}See Figures 2 and 3.



can be mapped to a particular range in memory, without the need for an external memory address decoder.

Figure 4. Using The SC22101 or SC22201 with an 8051 Microcontroller

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